


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/749,588	SEKIGUCHI ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Sy D. Luu	2174	

SEARCHED			
Class	Subclass	Date	Examiner
715	781,792, 806-807	9/30/2007	SL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
US-PGPUB		9/30/2007	SL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPAT US-PGPUB DERWENT EPO JPO	9/30/2007	SL
Text Searches: 715/781,790-797,803-804,806-807	9/30/2007	SL